

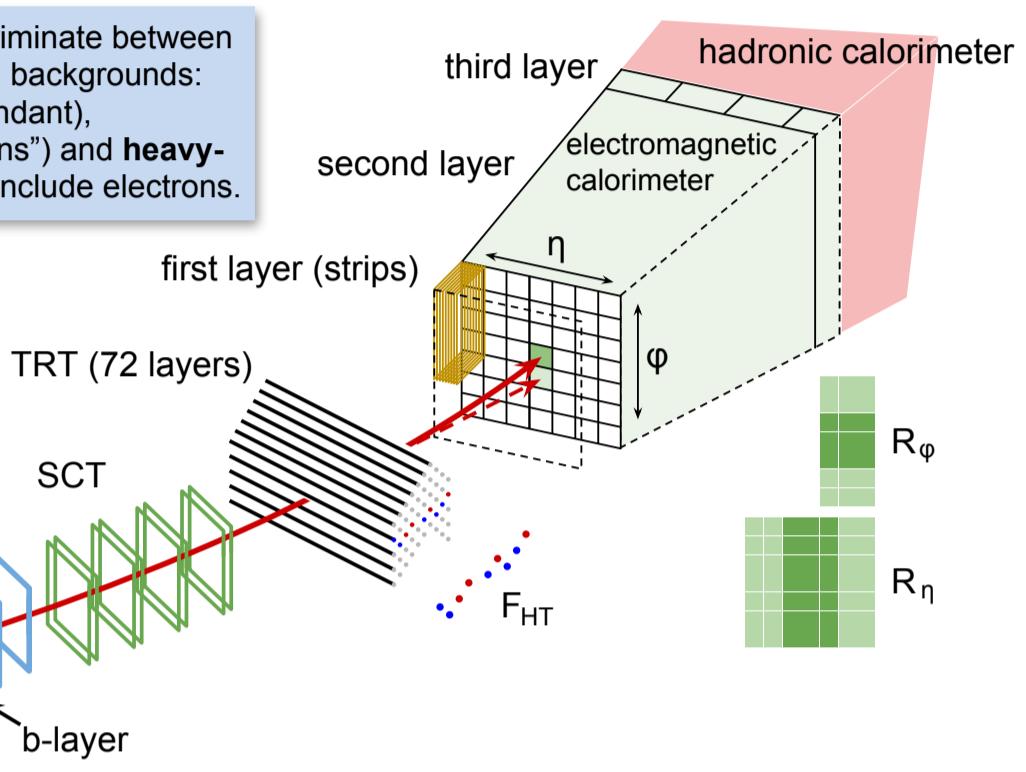
# Electron Identification and Efficiency Measurements in 2012

**Introduction:** The ATLAS Experiment requires efficient discrimination of electrons from backgrounds as a vital part of its physics program. Electron identification is achieved using Inner Detector and Electromagnetic Calorimeter quantities.

Electron efficiency measurements and uncertainties are needed for cross section measurements and searches. Electron efficiencies in the detector are measured and data-Monte Carlo correction factors are produced using in-situ methods with electrons from  $Z \rightarrow ee$  and  $J/\psi \rightarrow ee$  resonances.

## Electron Identification

Electron identification must discriminate between prompt electrons and three main backgrounds: **light-flavor hadrons** (most abundant), **converted photons** ("conversions") and **heavy-flavor hadrons**, whose decays include electrons.

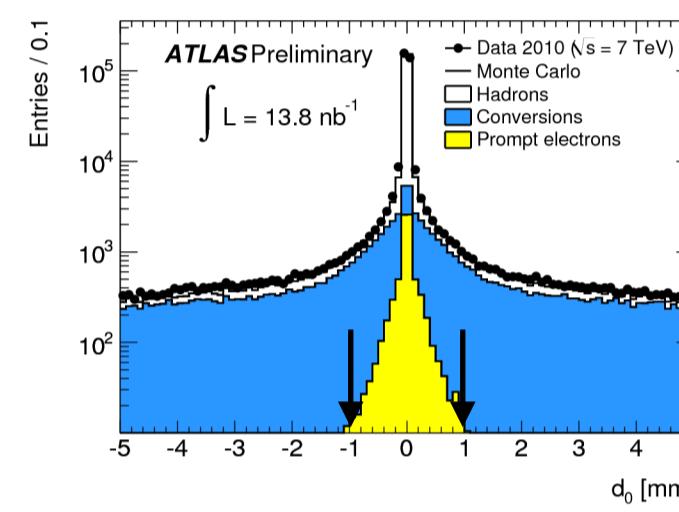


Electron identification uses **tracking**, **calorimeter**, and **track-calо matching** variables.

- **Track quality cuts** including number of b-layer hits, pixel+SCT hits and TRT hits
- $F_{HT}$ : TRT ratio of high-threshold to low-threshold hits, indicating electron transition radiation
- **Track parameters**: e.g.  $d_0$ , distance of closest approach to primary vertex
- **Calorimeter shower shapes**: energy ratios of cell clusters and layers, and lateral widths
- $R_{Had}$ , energy deposited in the hadronic calorimeter, divided by the cluster electromagnetic energy
- **Track-calorimeter matching**: distances between the extrapolated track and the electromagnetic cluster ( $\Delta\phi$  and  $\Delta\eta$ )

### Cut-based Identification method

- Simplest and most robust electron identification technique
- Rectangular cuts are applied to discriminating distributions to reject background.
- Used in 2011 and 2012 data-taking periods
- Re-optimized in 2012 to account for harsher pileup conditions
- Cut-based 2015 menus in preparation, with relaxed cuts on pileup-dependent variables



An illustration of the  $d_0$  variable for electrons, conversions and hadrons. The tight cut is indicated with arrows.

### Likelihood-based Identification method

- Developed for 2012 data-taking period
  - Constructed by creating probability distribution functions (pdfs) for signal and background distributions
  - Form discriminant based on the products of the pdfs evaluated for a given electron with variable values  $\vec{x}$ :
- $$d_L = \frac{\mathcal{L}_S}{\mathcal{L}_S + \mathcal{L}_B} \quad \text{with} \quad \mathcal{L}_S(\vec{x}) = \prod_{i=1}^n P_{S,i}(x_i)$$
- Cut on the discriminant  $d_L$  applied to define the selection
  - Designed to have the same signal efficiency as the 2012 cut-based menu, with better background rejection (see table).
  - Prepared for use offline and in the trigger in 2015.

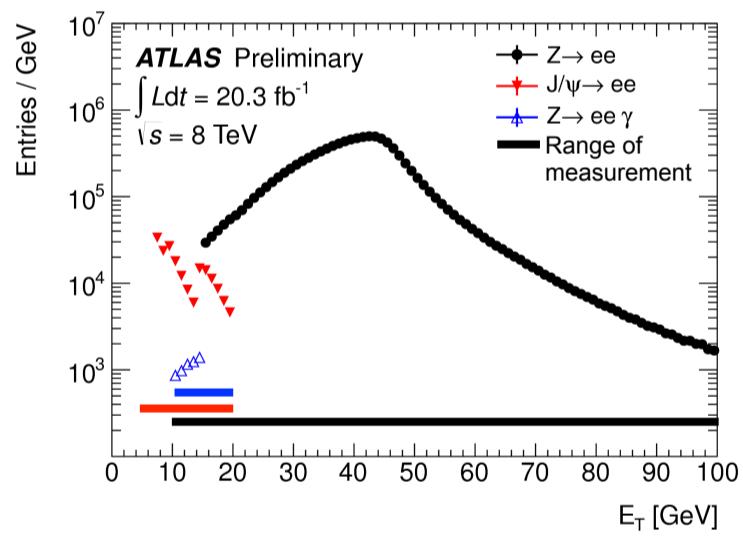
|             | Electron Efficiency in data | Background Efficiency (MC) |
|-------------|-----------------------------|----------------------------|
| Medium Cuts | $88.1 \pm 0.2\%$            | $1.11 \pm 0.02\%$          |
| Tight LH    | $87.8 \pm 0.3\%$            | $0.51 \pm 0.01\%$          |

## Electron Efficiency Measurements

Efficiencies are studied in data using the **tag and probe method**:

- Use  $Z \rightarrow ee$  and  $J/\psi \rightarrow ee$  events
- Events collected using single-electron triggers
- Strict identification requirements on the triggered electron ("tag")
- No requirement on the second "probe" electron
- Probe is unbiased source of electrons for efficiency measurements

Measurements performed in bins of  $E_T$  and  $\eta$



Number of probe electrons passing tight cuts.  
The bars below show the range of each method.

The total electron efficiency:

$$\epsilon_{\text{total}} = \epsilon_{\text{reconstruction}} \times \epsilon_{\text{identification}} \times \epsilon_{\text{trigger}}$$

- **Reconstructed electron**: electromagnetic cluster matched to a track passing basic tracking cuts
  - Measured with  $Z \rightarrow ee$  events, for  $E_T > 15$  GeV electrons
- **Identified electron**: passes cut-based or likelihood selection
  - High- $E_T$  electrons measured using  $Z \rightarrow ee$  methods
  - Low- $E_T$  electrons:  $J/\psi \rightarrow ee$ ,  $Z \rightarrow ee$  and  $Z \rightarrow eey$  (where the final state radiates a photon)

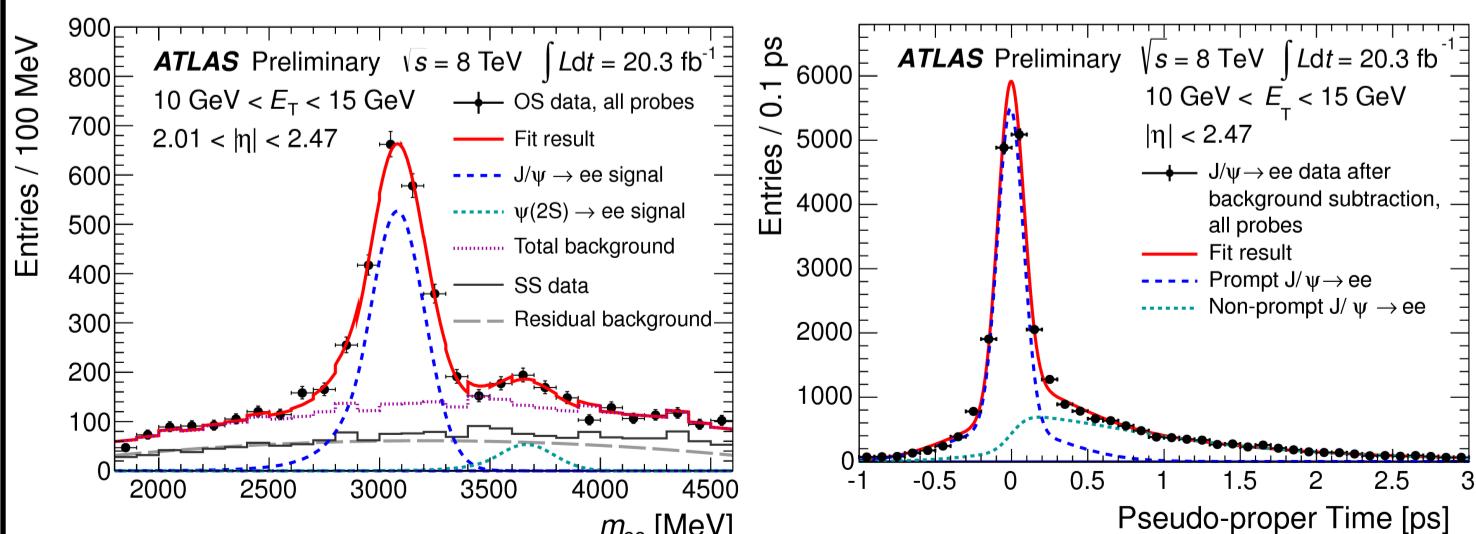
### Efficiency Methods using $Z \rightarrow ee$ Events

$Z \rightarrow ee$  decays have **prompt** and **non-prompt** contributions.

- Pseudo-proper time discriminates between the two

**Two  $J/\psi$  Efficiency Methods to measure prompt, isolated electrons:**

- Cut out events with large pseudo-proper time
- Fit pseudo-proper time to find prompt and non-prompt contributions



$$\text{Pseudo-proper Time: } \tau = \frac{L_{xy} \cdot m_{J/\psi}^{\text{PDG}}}{p_T^{J/\psi}}.$$

### Efficiency Methods using Zee Events: Mass and Isolation Methods

Select electron pairs with an invariant mass in a window around  $m_{ee} = 90$  GeV.

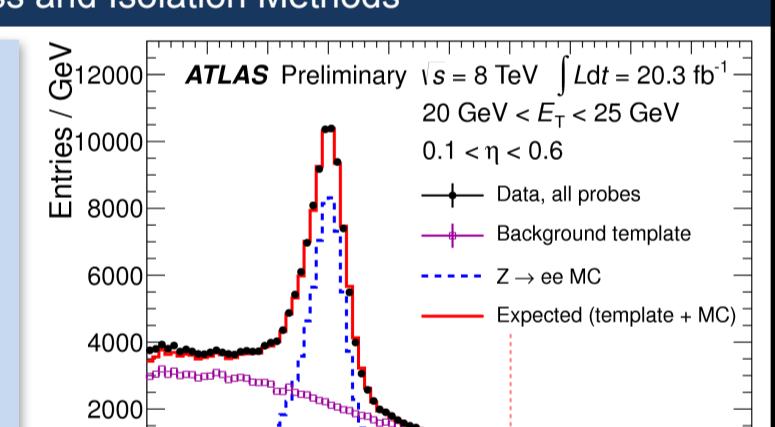
Background estimated using a **template method**.

- Tag and probe method is applied, but an identification menu or set of cuts is reversed
- Take background shape from this sample
- Normalized to a background-dominated region

**Two methods** used to measure efficiencies with different discriminating variables:

- $m_{ee}$  and **calorimeter isolation**

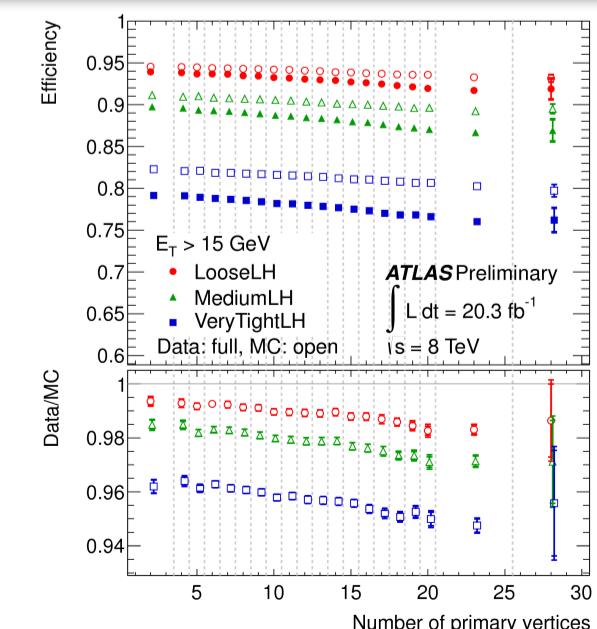
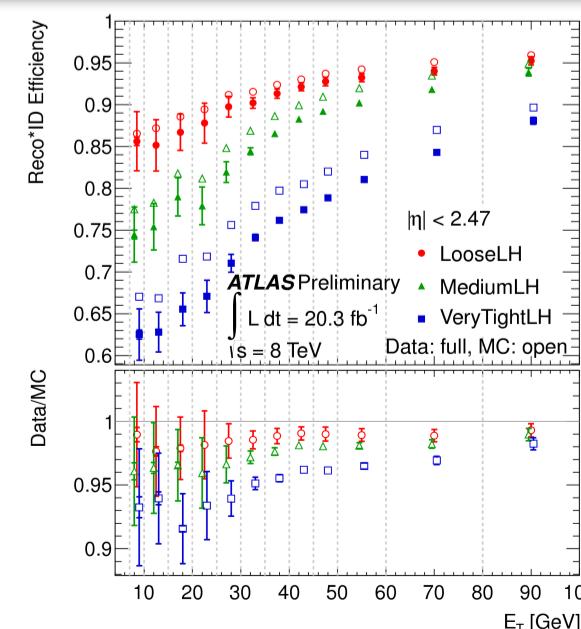
**Main uncertainty in both methods is background estimation at the probe level via templates.**



Top plot: all probes in the  $m_{ee}$  discriminant. Bottom: probes after applying tight cuts.

### Efficiency Measurement Results

Identification measurements from  $Z \rightarrow ee$ ,  $Z \rightarrow eey$  and  $J/\psi \rightarrow ee$  are combined using a global  $\chi^2$  fit which correlates systematic uncertainties between bins of  $E_T$  and  $\eta$  for a given method.



Efficiency measurements as a function of  $E_T$  (left) and number of primary vertices (right). Data-MC correction factors are shown in the ratio plots below.